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Form PTO-1449 US Dept. of Con (REV. 1/06) PATENT & TRADEMARK O						APPLICATION NO. New U.S. National 7 Stage & 1 0 7 PCT/JP2004/018435					
(Use several sheets if necessary)					APPLICANTS Hiroyuki NAGASAKA et al.						
				FILING DATE June 1, 2006							
		U.	S. PATEN	T DOCUM	MENTS						
Examiner Initials	Cite No.	Document Number	Date		N	ame					
/AM/	1.	2003/0139620 A1	07/24	/2003	YAMAGUCHI et al.						
× 000	2.	5,825,043	10/20/1998 08/24/1982 11/06/1984 03/11/1997		SUWA						
8	3.	4,346,164			TABARELLI et al.						
2000	4.	4,480,910			TAKANASHI et al.						
***************************************	5.	5,610,683			TAKAHASHI						
V	6.	5,715,039	02/03/1998		FUKUDA et al.						
/AM/	7.	2004/0165159 A1	08/26/2004		LOF et al.						
		FORE	EICNI DATI	ENIT DOC	NI MENTEC	_					
Examiner Initials	Cite No.	Document Number	EIGN PATENT Date		Country	With English Abstract	With English Translation				
/AM/	8.	JP-A-2003-240906	08/27	/2003	JAPAN	х	х				
200000	9.	JP-A-2003-238577	08/27	/2003	JAPAN	х	x				
	10.	WO 99/49504 A1	09/30/1999 11/13/1998		WIPO	х	х				
80000000	11.	JP-A-10-303114			JAPAN	х	х				
00000000	12.	JP-A-11-176727	07/02	/1999	JAPAN	х	х				
2000000	13.	JP-A-2004-207711	07/22	/2004	JAPAN	х	х				
2000000	14.	JP-A-04-305915	10/28	/1992	JAPAN	x					
0000000	15.	JP-A-04-305917 .	10/28	/1992	JAPAN	х					
	16.	JP-A-10-340846	12/22	/1998	JAPAN	х	х				
V	17.	JP-A-2000-058436	02/25	/2000	JAPAN	x	x				
/AM/	18.	JP-A-63-157419	06/30	/1988	JAPAN	х					
			OTHER E								
Examiner Initials	Examiner Cite (Including Author, Title, Date, Pertinent Pages, etc.) Initials No.										
EXAMINER /Alan Mathews/ Date considered 11/16/2009											
Examiner:	Initial if	citation considered, whether or not citati considered. Include copy of this form wit	ion is in co	nformanc	e with M.P.E.P. 609; draw line thr		conformance				

Date: June 1, 2006

Receipt date: 06/01/2006

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Form PTO-1449 US Dept. of Cor (REV. 1/06) PATENT & TRADEMARK O				ATTY DOCKET NO. 128253		10	APPLICATION NO. New U.S. National Stage of 1 PCT/JP2004/018433							
(Use several sheets if necessary)					APPLICANTS Hiroyuki NAGASAKA et al.									
				FILING DATE June 1, 2006										
		U.	S. PATEN	L DOCUM	IENTS									
Examiner Initials	Cite No.	Document Number	Date		Name									
FOREIGN PATENT DOCUMENTS														
Examiner Initials	Cite No.	Document Number	Da		Country		With English Abstract	With English Translation						
/AM/	19.	JP-A-58-202448	11/25/1983		JAPAN		х							
20000000	20.	JP-A-59-019912	02/01/1984		JAPAN		х							
	21.	JP-A-62-065326	03/24/1987		JAPAN		x							
	22.	JP-A-05-062877	03/12/1993		JAPAN		х	х						
20000	23.	JP-A-06-124873	05/06	/1994	JAPAN		х	х						
	24.	JP-A-07-220990	08/18	/1995	JAPAN		х	х						
***************************************	25.	JP-A-08-316125	11/29	/1996	JAPAN		х	х						
	26.	DD 221 563 A1	04/24	/1985	GERMANY		х	х						
V	27.	DD 224 448 A1	07/03	/1985	GERMANY		х	х						
/AM/	28.	WO 2004/019128 A2	03/04	/2004	WIPO									
						1	· <u>·</u> ··································							
					MIDO									
					WIPO									
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			071155	200717	NTS			<u> </u>						
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EXAMINER /Alan Mathews/ Date consider 11/16/2009														
Examiner:		citation considered, whether or not citation considered. Include copy of this form wit				through ci	tation if not in	n conformance						

Date: June 1, 2006